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Advances in Scanning Probe Microscopy

With 241 Figures



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Contents

1 Theory of Scanning Probe Microscopy	
Naruo Sasaki and Masaru Tsukada	1
1.1 Introduction	1
1.2 Scanning Tunneling Microscopy	3
1.3 Frictional Force Microscopy	9
1.4 Dynamic-Mode Atomic Force Microscopy	21
1.5 Non-Contact Mode Atomic Force Microscopy	31
1.6 Conclusion	38
References	40
2 The Theoretical Basis of Scanning Tunneling Microscopy for Semiconductors – First-Principles Electronic Structure Theory for Semiconductor Surfaces	
Takahisa Ohno	43
2.1 Introduction	43
2.2 Computational Methods	44
2.3 Surface Structures	47
2.4 Surface Dynamics	53
References	63
3 Atomic Structure of 6H-SiC (0001) and (000$\bar{1}$)	
L. Li and T. Sakurai	65
3.1 Introduction	65
3.2 Surface Preparation	67
3.3 Surface Structure of 6H-SiC (0001) and (000 $\bar{1}$)	68
3.4 Surface Phonons of 6H-SiC (0001)	82
3.5 Effect of Surface Polarity for Gallium Adsorption onto 6H-SiC Surfaces	84
3.6 Conclusions	88
References	89

4 Application of Atom Manipulation for Fabricating Nanoscale and Atomic-Scale Structures on Si Surfaces

T. Hashizume, S. Heike, T. Hitosugi and K. Kitazawa	91
4.1 Introduction	91
4.2 Experimental Aspects	93
4.3 Property Changes in the Si(111)-7×7 Surface	94
4.4 Properties of Dangling Bonds on the Si(100)-2×1-H Surface	99
4.5 Interaction of Adsorbates with Dangling Bonds on Si(100)-2×1-H Surfaces and Atomic Wire Fabrication	106
4.6 Conclusion	111
References	111

5 Theoretical Insights into Fullerenes Adsorbed on Surfaces: Comparison with STM Studies

Kaoru Ohno and Yoshiyuki Kawazoe	113
5.1 Introduction	113
5.2 Fullerene Research Background	115
5.3 Universal Features of C ₆₀ and C ₇₀ STM Images	117
5.4 Dipole Field Caused by Charge Transfer	124
5.5 Photo-Induced Excited States	129
5.6 Conclusion	135
Appendix: All-Electron Mixed Basis Approach	136
References	139

6 Apparent Barrier Height and Barrier-Height Imaging of Surfaces

Akira Sakai	143
6.1 Introduction	143
6.2 Properties of Barrier Height	145
6.3 Measurements of Barrier Height	153
6.4 Barrier-Height Imaging	155
6.5 Applications of BH Imaging	158
References	163

7 Mesoscopic Work Function Measurement by Scanning Tunneling Microscopy

Y. Hasegawa, J.F. Jia, T. Sakurai, Z.Q. Li, K. Ohno and Y. Kawazoe	167
7.1 Introduction	167
7.2 Work Function	168
7.3 Experimental Techniques	174
7.4 Results	179
7.5 Conclusion	190
References	190

8 Scanning Tunneling Microscopy of III–V Compound Semiconductor (001) Surfaces	
Qi-Kun Xue, T. Hashizume and T. Sakurai	193
8.1 Introduction	193
8.2 Semiconductor Surface Reconstruction	195
8.3 GaAs(001) As-Rich Surface	200
8.4 GaAs(001) Ga-Rich Surface	227
8.5 Other Arsenide (001) Surfaces	243
8.6 Phosphide, Antimonide and Nitride (001) Surfaces	261
8.7 Conclusions	273
References	276
9 Adsorption of Fullerenes on Semiconductor and Metal Surfaces	
Investigated by Field-Ion Scanning Tunneling Microscopy	
T. Hashizume and T. Sakurai	283
9.1 Introduction	283
9.2 Experiment	285
9.3 Results and Discussions on Semiconductor Substrates	288
9.4 Results and Discussions on Metal Substrates	313
9.5 Conclusions	332
References	333
Index	339